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(19) **United States**(12) **Patent Application Publication**
Jeon(10) **Pub. No.: US 2002/0045818 A1**(43) **Pub. Date: Apr. 18, 2002**(54) **INTERGRATED CIRCUIT FOR
GENERATING A HIGH-VOLTAGE PULSE
FOR USE IN AN ULTRASOUND
DIAGNOSTIC SYSTEM**(30) **Foreign Application Priority Data**

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Publication Classification(51) **Int. Cl.⁷** **A61B 8/00**(52) **U.S. Cl.** **600/437**(57) **ABSTRACT**

An integrated circuit generates a high-voltage coded excitation pulse for use in producing a sharply defined diagnostic image in an ultrasound diagnostic system. The integrated circuit comprises at least two signal generator for generating a driving signal and a pulser, responsive to the driving signal, for creating a pulse sequence constructed by a combination of a first and a second voltage level, wherein the pulse sequence is made of a random code sequence.

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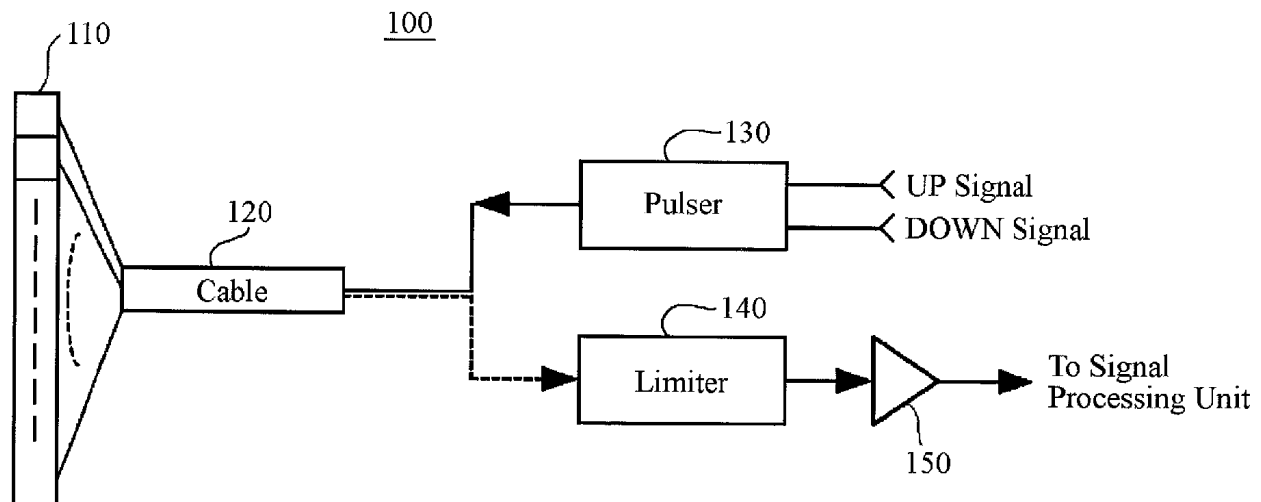
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Fig. 1

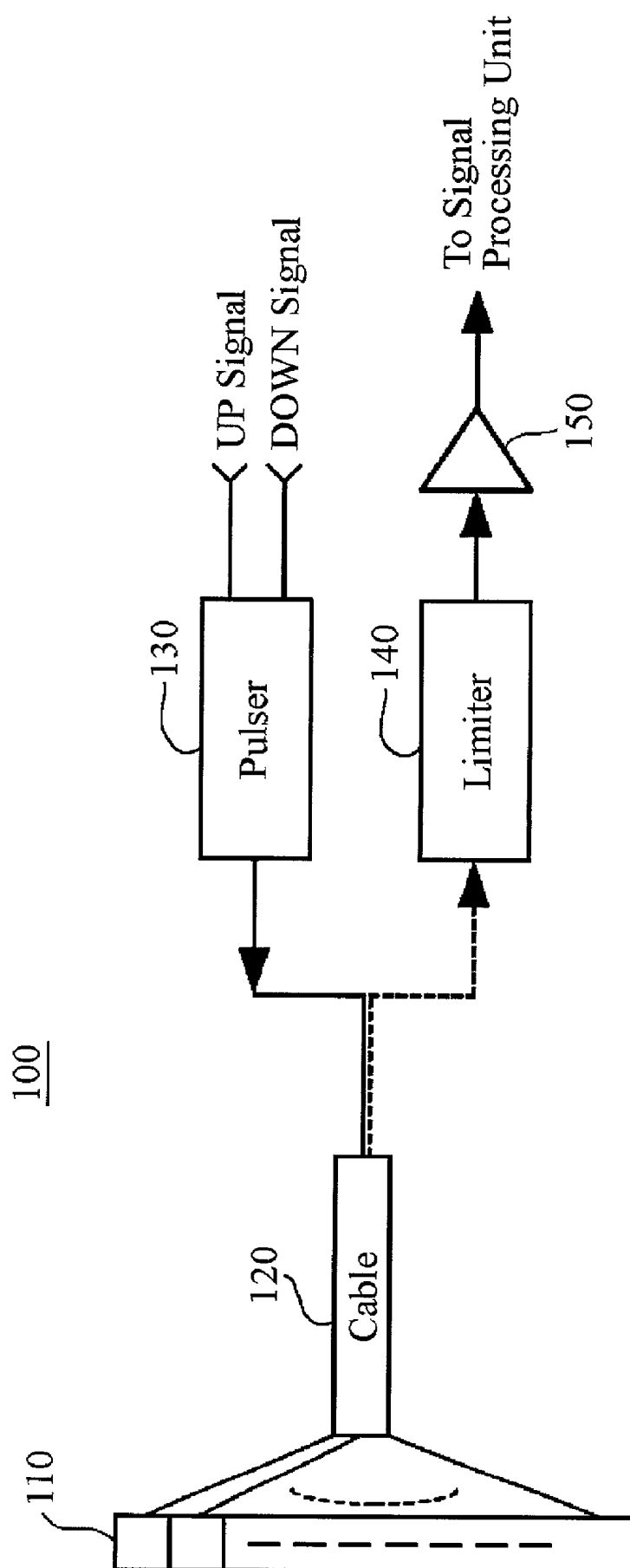


Fig. 2
(Prior Art)

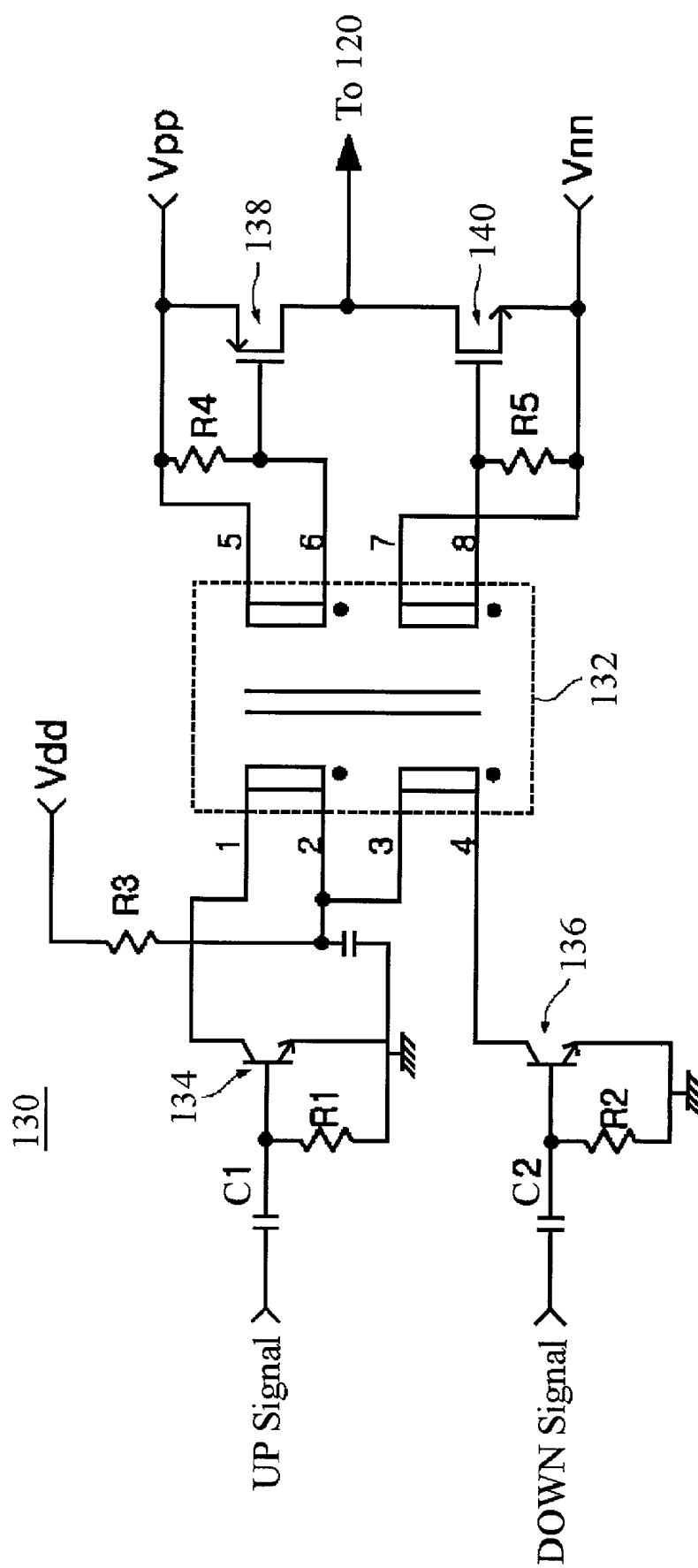


Fig. 3A

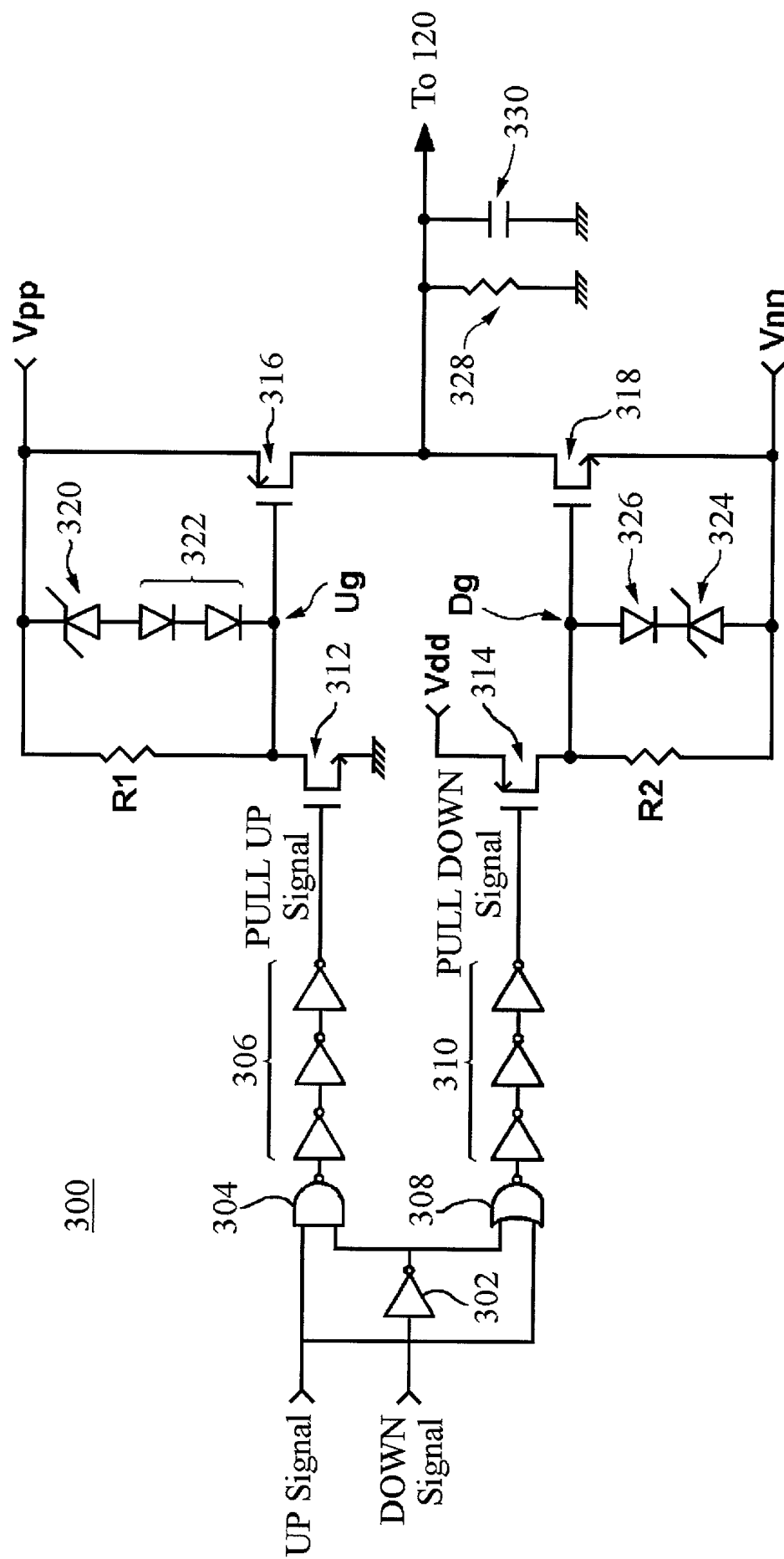


Fig. 3B

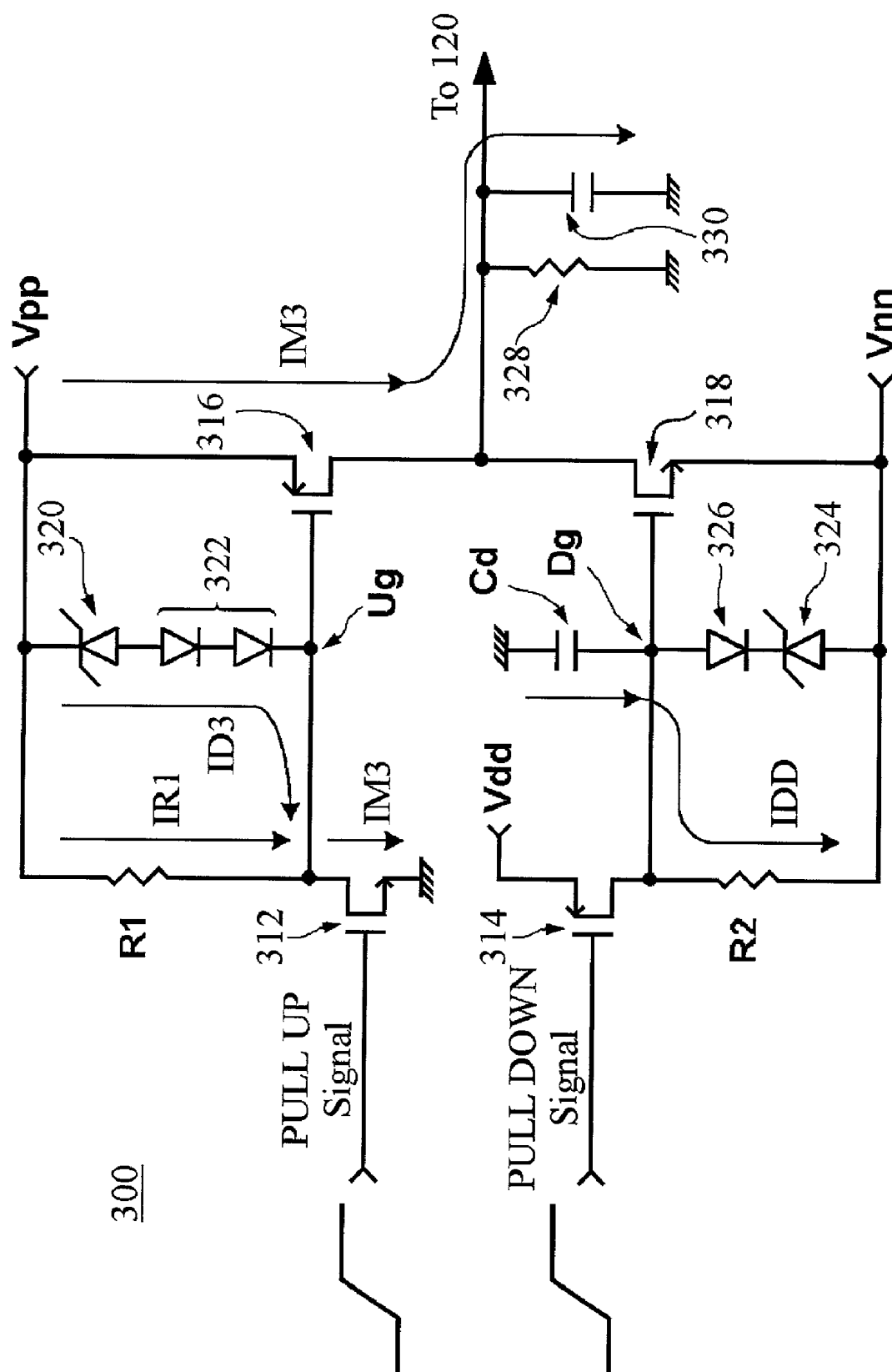


Fig. 3C

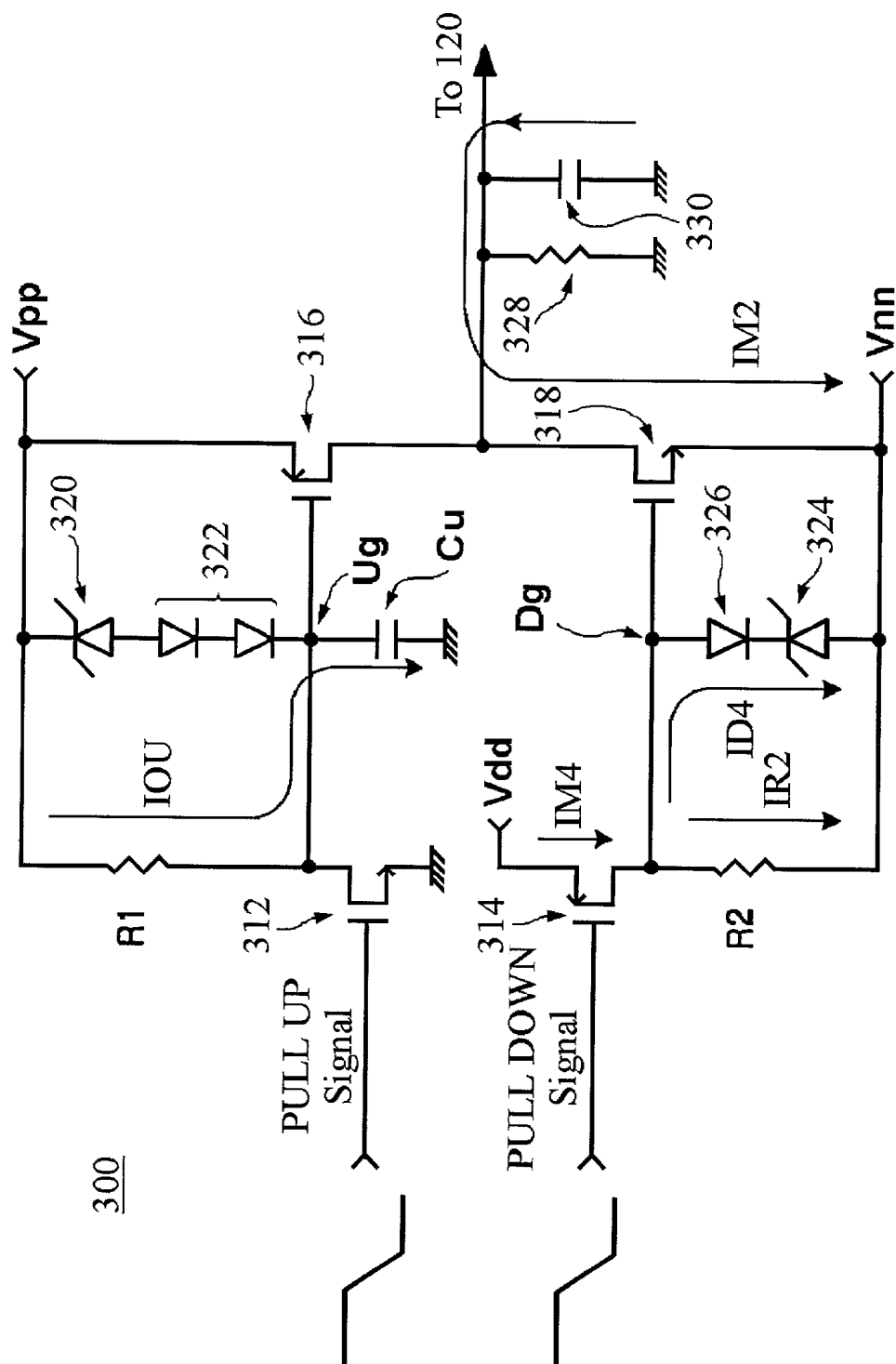


Fig. 4

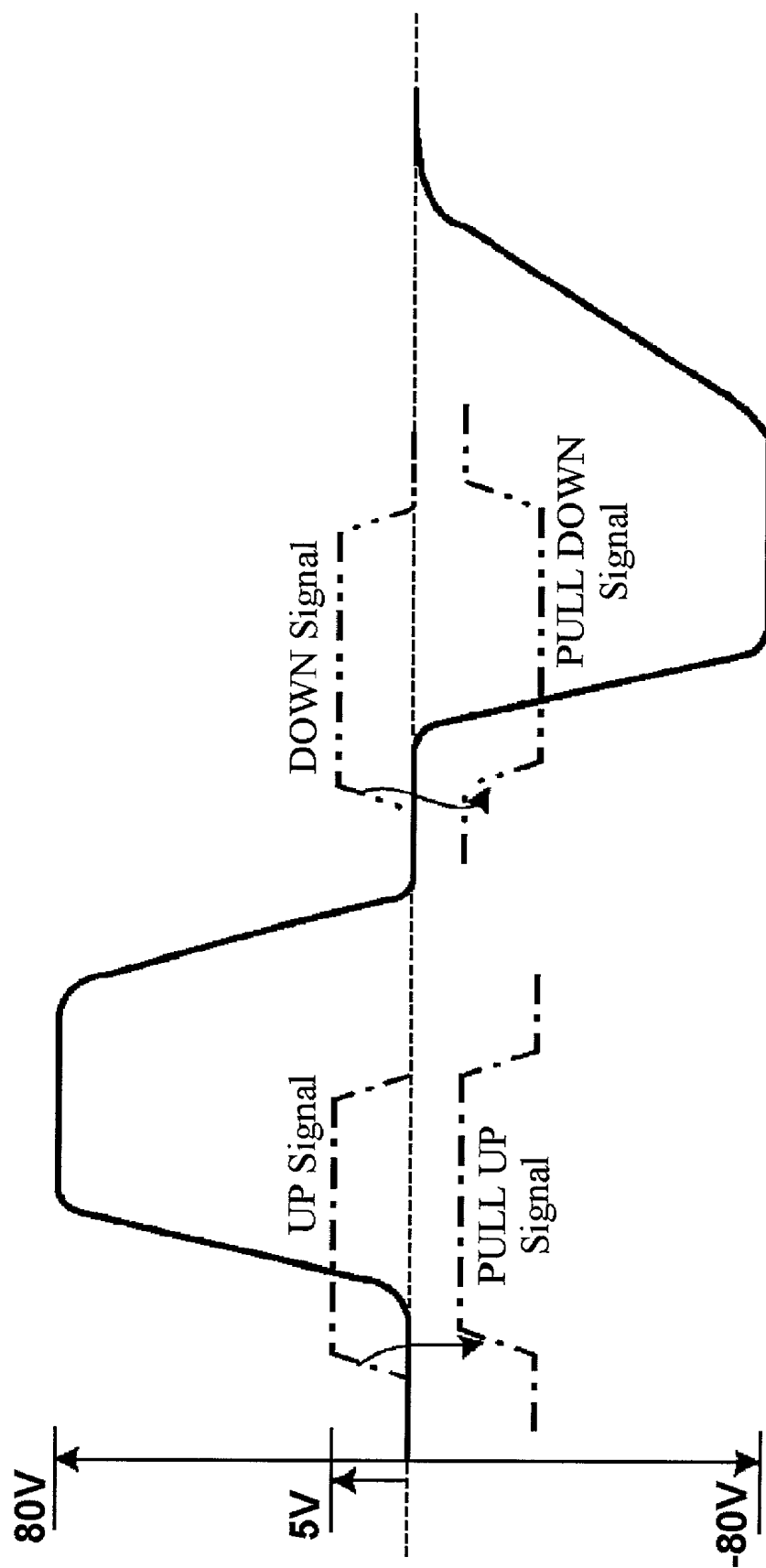


Fig. 5A

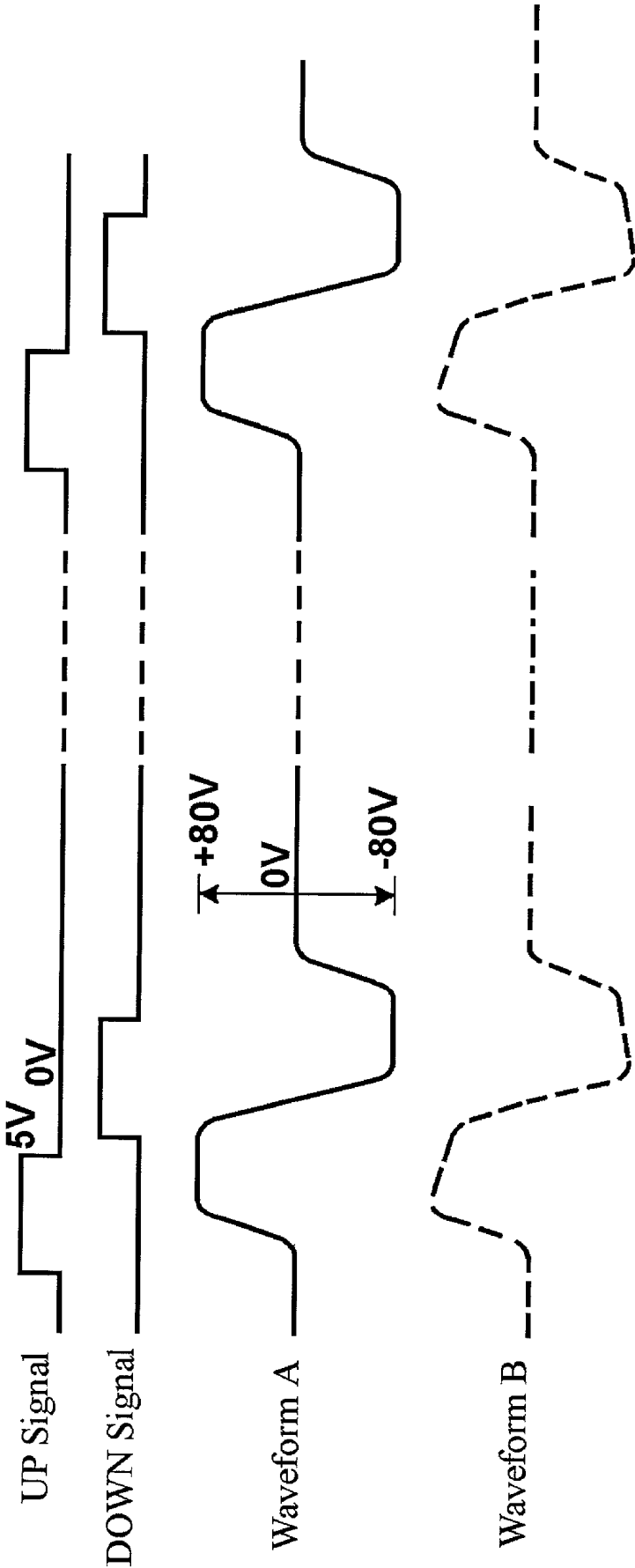


Fig. 5B

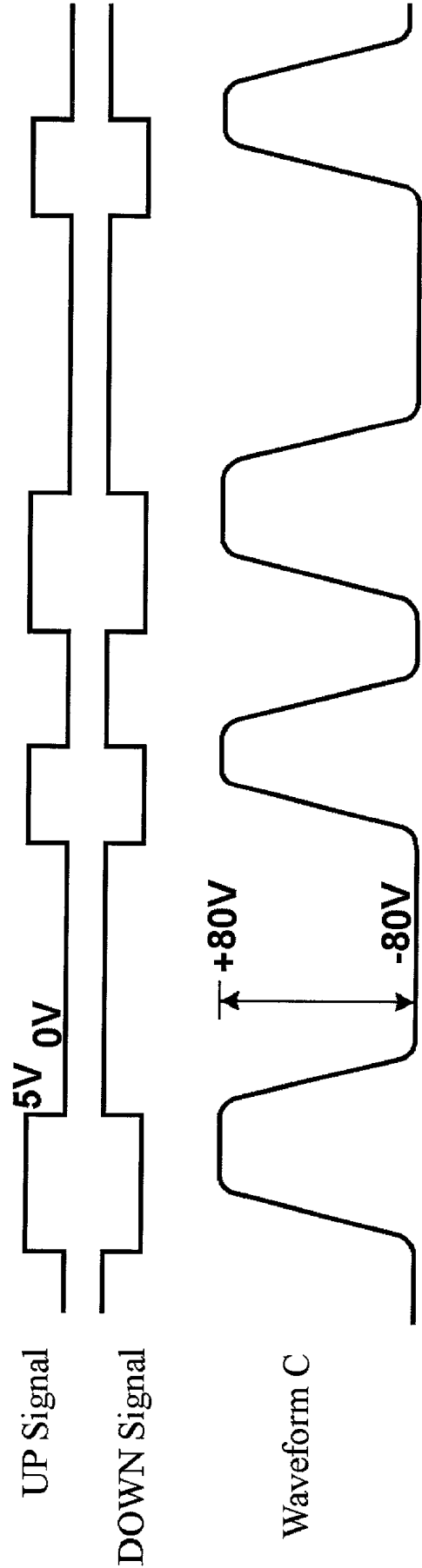
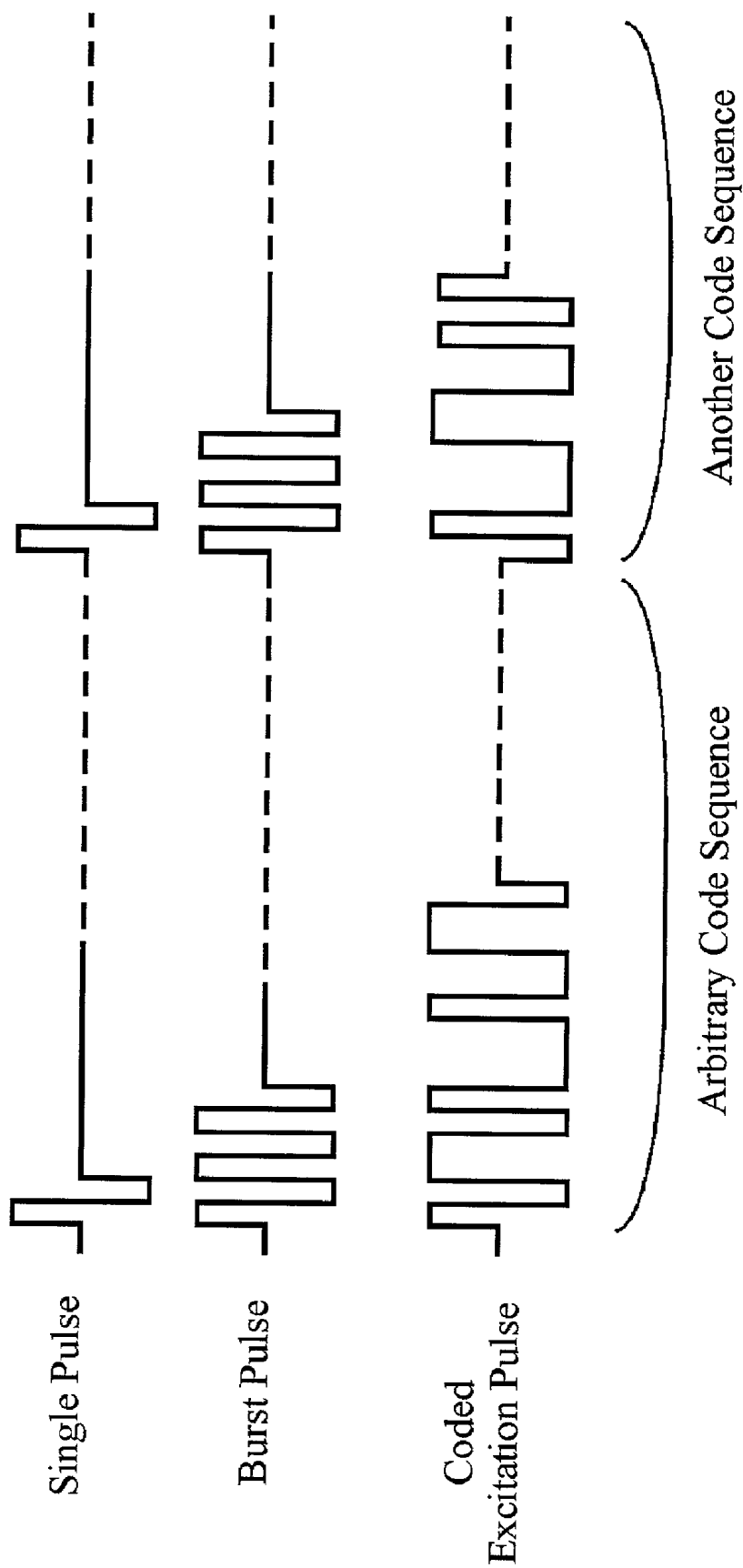


Fig. 6



INTERGRATED CIRCUIT FOR GENERATING A HIGH-VOLTAGE PULSE FOR USE IN AN ULTRASOUND DIAGNOSTIC SYSTEM

BACKGROUND OF THE INVENTION

[0001] 1. Field of the Invention

[0002] The present invention relates to an ultrasound diagnostic system; and, more particularly, to an integrated circuit for use in the system for generating a high-voltage coded excitation pulse to be used in producing a sharply defined diagnostic image.

[0003] 2. Description of the Related Art

[0004] An ultrasound diagnostic system is gaining popularity in medical applications for obtaining a diagnostic image of an anatomy in a human body. An ultrasound signal is generated by a transducer or an array of transducers, which convert electrical energy into acoustic energy for transmission into an object to be examined. The transducer may also receive echoes indicative of discontinuities or impedance variations on the ultrasound signal reflected from the object. The received echoes are processed by the transducer, i.e., converted to an electrical signal. The electrical signal is amplified and decoded to produce an image of the object.

[0005] Typically, in order to generate an ultrasound signal, a high-voltage pulse is advantageously used. Pulses would have a predefined voltage level, e.g., ranging from -80 V (volts) to +80 V, or from zero to +200 V. One should be able to control the voltage levels without causing unexpected damage or harm to a target object, specifically those within a human body. Details of the voltage level adjustment will be explained with reference to FIGS. 1 and 2 below.

[0006] FIG. 1 shows a block diagram of a unit 100 for transmitting and receiving ultrasound signals. The unit 100 comprises a transducer 110, a cable 120, a pulser 130, a limiter 140 and a pre-amplifier 150. The pulser 130 receives UP and DOWN signals from a signal generator (not shown). In response to the UP and DOWN signals, the pulser 130 generates high-voltage pulses for use in the generation of the ultrasound signals. The high-voltage pulses are outputted through the cable 120 to the transducer 110, which in turn. In response to the high-voltage pulses from the pulser 130, the transducer 110 generates and transmits ultrasound signals to an object (not shown) within a human body to be examined. The ultrasound signals generated by the transducer 110 would have a resonant frequency and acoustic energy as determined by electrical energy carried by the high-voltage pulses.

[0007] Transmitted ultrasound signals are reflected and received by the transducer 110. The transducer 110 converts the reflected ultrasound signals back to electrical signals corresponding thereto. The electrical signals are provided via the cable 120 to the limiter 140 before outputted to the pre-amplifier 150. The pre-amplifier 150 amplifies the electrical signals to a predetermined level to transmit it to a signal processing unit (not shown).

[0008] The pulser 130 is required to provide a current of 2 A (ampere) for generating the high-voltage pulses, since it is connected to the cable 120 of, e.g., 400 pF (pico-Faraday) having a capacitive load of the transducer 110 and to the

limiter 140 having an input impedance of, e.g., 100 Ω (ohm). It is also necessary that the rising and falling times of the high-voltage pulses should be less than 20 ns (nanosecond), because the pulse frequency suitable for generating the ultrasound signals must be at least 12 MHz (Mega-Hertz). In other words, the high-voltage pulse width should be within 40 ns. Conventional pulsers commonly include a step-up transformer in order to satisfy the aforementioned requirements.

[0009] FIG. 2 illustrates a circuit diagram of the pulser 130 according to the prior art. It is constructed by including a step-up transformer 132. For the convenience of explanation, the left portion, i.e., a primary winding side of the step-up transformer 132 is referred to as an input part, whereas the right portion, i.e., a secondary winding side thereof is called an output part. And, for the purpose of simplicity, the principle of an operation of the transformer 132 is omitted as it is well known in the art.

[0010] UP and DOWN signals are provided to the pulser 130 through different paths, wherein the UP and DOWN signals are each a digital signal having a voltage level ranging 0 to 5 V, for instance. The UP signal is provided to the base of a transistor 134 through a capacitor C1, while the DOWN signal is inputted to the base of a transistor 136 via a capacitor C2. The collectors of the transistors 134 and 136 are connected to the primary winding of the step-up transformer 132. As the UP and DOWN signals are inputted, the step-up transformer 132 serves as a level shifter to allow CMOS (Complementary Metal Oxide Semiconductor) transistors 138 and 140 to generate a high-voltage pulse, the transistors 138 and 140 being connected to the secondary winding of the transformer 132. Such generated high-voltage pulse is then transmitted to the cable 120 shown in FIG. 1.

[0011] Specifically, the pulser 130 according to the prior art generates a single high-voltage or a burst high-voltage pulse shown in FIG. 6, depending on a part of an object within the human body to be examined or a color diagnostic image thereof. In the single high-voltage pulse or the burst high-voltage pulse, the width of each of logic high and logic low thereof has a range from maximum 500 ns to minimum 30 ns. In this circuit arrangement, when the UP signal changes from logic low to logic high, the output voltage from the pulser 130 would reach a voltage V_{pp} applied to the CMOS transistor 138. Although the UP signal remains in logic high for a certain time, the output voltage V_{pp} is no longer maintained after that time and thus returns to 0 V. Upon transiting from logic low to logic high of the UP signal, a voltage across a resistor R4 returns from V_{pp} to zero. The resistor R4 is connected to V_{pp} , to the secondary winding of the step-up transformer 132 and to the gate of the CMOS transistor 138. When the DOWN signal is changed from logic low to logic high, a similar phenomenon as described above is occurred. As well known in the art, these results from an electromotive force of the transformer 132, wherein the electromotive force is created only by a current alternation flowing on the primary winding of transformer 132.

[0012] Recently, in order to obtain a sharply defined diagnostic image, a method for combining transducers or filtering reflected ultrasound signals has been studied in depth. As well as such method, a circuit device for gener-

ating high-voltage pulses for use in generating ultrasound signals has been also studied in further detail. It is well known to those skilled in the art that high-voltage coded excitation pulses containing an arbitrary code sequence are very effective in producing the sharply defined a random pulse sequence which is comprised of first and second voltage levels.

[0013] In accordance with another aspect of the present invention, there is provided an integrated circuit for providing an electrical signal for use in generating an ultrasound signal in an ultrasound diagnostic system, comprising: at least two signal generators for generating a control signal; and a pulser, responsive to the control signal, for providing the electrical signal having first and second signal levels, wherein the electrical signal includes a random code represented by a combination of the first and second signal levels.

BRIEF DESCRIPTIONS OF THE DRAWINGS

[0014] The above and other objects and features of the present invention will become apparent from the following description of a preferred embodiment given in conjunction with the accompanying drawings, in which:

[0015] **FIG. 1** shows a block diagram of a typical unit for transmitting and receiving an ultrasound signal;

[0016] **FIG. 2** depicts a circuit diagram of a pulser according to the prior art;

[0017] **FIG. 3A** exemplifies a circuit diagram of a pulser in accordance with the present invention;

[0018] **FIGS. 3B and 3C** illustrate diagrams for explaining the operation of the pulser shown in **FIG. 3A**;

[0019] **FIG. 4** presents a waveform of a single pulse generated by the pulser in accordance with the present invention;

[0020] **FIG. 5A** is a diagram for comparing the waveform of a single pulse generated by the pulser shown in **FIG. 2** with that of the single pulse generated by the pulser shown in **FIG. 3A**;

[0021] **FIG. 5B** is a diagram of a high-voltage coded excitation pulse generated by the pulser in accordance with the present invention; and

[0022] **FIG. 6** represents a diagram for explaining single, burst, and high-voltage coded excitation pulses.

DETAILED DESCRIPTION OF THE PRESENT INVENTION

[0023] **FIG. 3A** shows a circuit diagram of a pulser **300** in accordance with the present invention. An UP signal is inputted to an input port of a NAND gate **304** as well as an input port of a NOR gate **308**, while a DOWN signal is provided to an inverter **302**. The output of the inverter **302** is commonly coupled to the other input ports of the NAND gate **304** and the NOR gate **308**. Like the prior art, each of the UP and DOWN signals is a digital signal having a voltage level of 0 to 5 V, for instance. The output signal of the pulser **300** becomes logic high when the UP signal is logic high, and changes to logic low when the DOWN signal is logic low.

[0024] The output signal of the NAND gate **304** is transmitted through a series of inverters **306**, to finally become a PULL UP signal. Similarly, the output signal of the NOR gate **308** is provided to a series of inverters **310** to finally become a PULL DOWN signal. The PULL UP and PULL DOWN signals are provided to the gate of a high-voltage n-type CMOS transistor **312** and to the gate of a high-voltage p-type CMOS transistor **314**, respectively. These have a voltage level of, e.g., 0 to 5 V and are used to drive the high-voltage CMOS transistors **312** and **314**, respectively.

[0025] The source of the high-voltage n-type CMOS transistor **312** is grounded and its drain is coupled to one terminal of a resistor **R1** of, e.g., 60 Ω , to the cathode of a series of diodes **322** and to the gate of a high-voltage CMOS transistor **316**. The other terminal of the resistor **R1** is connected to the cathode of a Zener diode **320** and to Vpp; and the anode of the diodes **322** is coupled to that of the Zener diode **320**. The cathode of the Zener diode **320** is connected to Vpp. Vpp has a voltage level of +80 V, for instance. The source of the high-voltage p-type CMOS transistor **314** is connected to Vdd having a voltage level of +5 V, for instance. The drain thereof is coupled to one terminal of a resistor **R2**, to the anode of a diode **326** and to the gate of a high-voltage CMOS transistor **318**. The cathode of the diode **326** is coupled to that of a Zener diode **324**. The anode of the Zener diode **324** and the other terminal of the resistor **R2** are connected to Vnn having a voltage level of, -80 V, for instance. It should be interpreted and understood that the term "high-voltage" used here means an absolute voltage value greater than a range of 0 to +5 V, but is not limited to the exemplary range of, +80 V to -80 V.

[0026] Now, the details of the pulser **300** in accordance with the present invention will be described with reference to **FIGS. 3B** to **6**.

[0027] In **FIG. 3B**, when the UP signal is logic high and the DOWN signal is logic low, the PULL UP and PULL DOWN signals change from logic low to logic high. In response to the PULL UP signal, the CMOS transistor **312** is turned on so that a current IR1 flows through the resistor **R1**, while a current ID3 flows through the Zener diode **320** and the diodes **322**. Then, a voltage about 8 V (the sum of the breakdown voltage of the Zener diode **320** and the turn-on voltages of the diodes **322**) is seen between Vpp and a node Ug, which is at the gate of a transistor **316**. That voltage is sufficient to drive the CMOS transistor **316**. On the other hand, the CMOS transistor **314**, responsive to the PULL DOWN signal of logic high, is turned off to discharge a parasitic capacitor Cd on a node Dg such that a current IOD flows toward Vnn through the resistor **R2**. At this time, a voltage level at the node Dg, which is at the gate of a transistor **318** becomes Vnn. Thus, the CMOS transistor **318** is turned off. As a result, a current IM3 flows from Vpp through the CMOS transistor **316** to a load capacitor **330**. The load capacitor **330** is charged by the current IM3, so that the output voltage of the pulser **300** rises to Vpp of +80 V, as shown in **FIG. 4** and a waveform A of **FIG. 5A**. It should be noted that the Zener diode **320** and the diodes **322** serve to prevent the gate of the CMOS transistor **316** from breaking down due to an issuance of an undesirable high-voltage.

[0028] When the UP signal is logic low and the DOWN signal is logic high, the PULL UP and PULL DOWN signals

change from logic high to logic low as shown in **FIG. 3C**. In response to the PULL UP signal of logic low, the CMOS transistor **312** is turned off so that a parasitic capacitor C_u on the node U_g is charged by a current I_{OU} flowing through the resistor **R1**. At this time, the voltage at the node U_g becomes V_{pp} . Thus, there is no sufficient voltage difference to drive the CMOS transistor **316**. As a result, the CMOS transistor **316** is turned off. On the other hand, the CMOS transistor **314**, responsive to the PULL DOWN signal of logic low, is turned on so that a current I_{M4} flows from the source of the CMOS transistor **314** to the drain thereof. The current I_{M4} is divided into two, one of which, i.e., a current I_{R2} flows via the resistor **R2** and the other of which, i.e., a current I_{D4} flows via the diode **326** and the Zener diode **324** to V_{nn} . As a result, the voltage at the node D_g rises to, approximately, 6.5 V from V_{nn} . Since this voltage of 6.5 V is also between the gate and the source of the CMOS transistor **318**, the CMOS transistor **318** becomes conductive.

[0029] As described above, when the CMOS transistor **316** is turned off and the CMOS transistor **318** is turned on, a current I_{M2} flows toward V_{nn} through the CMOS transistor **318** as the load capacitor **330** begins to discharge. As a result, the output voltage of the pulser **300** falls to V_{nn} of -80 V, as shown in **FIG. 4** and a waveform A of **FIG. 5A**. It should be noted that the Zener diode **324** and the diode **326** serve to prevent the gate of the CMOS transistor **318** from breaking down by an undesirable high-voltage.

[0030] When both of the UP and DOWN signals are logic low, the PULL UP signal would be logic low and the PULL DOWN signal would be logic high. Then, the voltage at the node U_g becomes V_{pp} , while the voltage at the node D_g becomes V_{nn} . Thus, both of the CMOS transistors **316** and **318** are turned off and a voltage across a load resistor **328** falls to 0 V, as shown in a waveform A of **FIG. 5A**. Consequently, the output voltage of the pulser **300** becomes 0 V.

[0031] In case that the PULL UP and PULL DOWN signals are either logic high or logic low for a predetermined time, the output voltage of the pulser **300** remains in its current logic state until the PULL UP and PULL DOWN signals change to the other logic level, as shown in a waveform C of **FIG. 5B**. Therefore, the pulser **300** in accordance with the present invention could generate a high-voltage coded spirit and the scope of the claims appended hereto.

What is claimed is:

1. A circuit for generating a pulse to be used in producing an ultrasound image, comprising:

at least two means for generating a driving signal; and

means, responsive to the driving signal, for creating a random sequence of pulses comprised of first and second voltage levels.

2. The circuit according to claim 1, wherein the random sequence of pulses is created based on the driving signal.

3. The circuit according to claim 1, wherein the driving signal has logic high and logic low states.

4. The circuit according to claim 1, wherein said at least two means for generating the driving signal and the means for creating the random sequence of pulses are integrated on one unit.

5. The circuit according to claim 1, wherein the first and second voltage levels have positive and negative voltage levels, respectively.

6. The circuit according to claim 4, wherein the means for creating the random sequence of pulses includes at least two switching means operating in response to the driving signal.

7. The circuit according to claim 4, wherein the means for generating the driving signal includes at least one logic gate and a plurality of inverters connected electrically to said at least one logic gate.

8. The circuit according to claim 7, wherein said at least one logic gate is one of a NAND gate and a NOR gate.

9. The circuit according to claim 6, wherein said at least two switching means are each a CMOS (Complementary Metal Oxide Semiconductor) transistor.

10. The circuit according to claim 6, wherein the means for creating the random sequence of pulses further includes more than one diode for preventing from breaking down said at least two switching means connected electrically thereto.

11. An integrated circuit for providing an electrical signal for use in generating an ultrasound signal in an ultrasound diagnostic system, comprising:

at least two means for generating a control signal; and

means, responsive to the control signal, for providing the electrical signal having first and second signal levels,

wherein the electrical signal includes a random code represented by a combination of the first and the second signal levels.

12. The integrated circuit according to claim 11, wherein the random code is used for producing a diagnostic image, wherein the diagnostic image represents an internal shape of an object to be examined.

13. The integrated circuit according to claim 12, wherein the random code is generated based on the control signal.

14. The integrated circuit according to claim 11, wherein the electrical signal has the form of a pulse sequence.

15. The integrated circuit according to claim 11, wherein the control signal has logic high and logic low states.

16. The integrated circuit according to claim 11, wherein the means for providing the electrical signal includes at least two switching means operating in response to the control signal.

17. The integrated circuit according to claim 11, wherein said at least two means for generating the control signal include at least one logic gate and a plurality of inverters connected electrically to said at least one logic gate.

18. The integrated circuit according to claim 17, wherein said at least one logic gate includes one of a NAND gate and a NOR gate.

19. The integrated circuit according to claim 16, wherein said at least two switching means are each a CMOS transistor.

20. The integrated circuit according to claim 16, wherein the means for providing the electrical signal further includes more than one diode for preventing from breaking down said at least two switching means connected electrically thereto.

专利名称(译)	用于产生用于超声诊断系统的高压脉冲的集成电路		
公开(公告)号	US20020045818A1	公开(公告)日	2002-04-18
申请号	US09/909521	申请日	2001-07-20
申请(专利权)人(译)	MEDISON CO. , LTD.		
当前申请(专利权)人(译)	MEDISON CO. , LTD.		
[标]发明人	JEON KI		
发明人	JEON, KI		
IPC分类号	A61B8/00 B06B1/02		
CPC分类号	B06B2201/76 B06B1/0215		
优先权	1020000059925 2000-10-12 KR		
外部链接	Espacenet USPTO		

摘要(译)

集成电路产生高压编码激励脉冲，用于在超声诊断系统中产生清晰定义的诊断图像。集成电路包括至少两个用于产生驱动信号的信号发生器和响应于驱动信号的脉冲发生器，用于产生由第一和第二电压电平的组合构成的脉冲序列，其中脉冲序列由随机码序列。

